Notice of References Cited Application/Control No. 10/533,712 Examiner HENOK G. HEYI Applicant(s)/Patent Under Reexamination LOW, YEE CHEOK Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,646,278 A	02-1987	Okano, Takashi	369/30.12
*	В	US-5,847,719 A	12-1998	Yamaguchi et al.	346/134
*	С	US-6,175,538 B1	01-2001	Ogata, Hitoshi	369/30.16
*	D	US-6,320,824 B1	11-2001	Hirata, Minoru	369/53.29
*	Е	US-2003/0072237 A1	04-2003	Hashimoto et al.	369/53.28
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	7	US-			
	K	US-			
	┙	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	C						
	>						
	w						
	х						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.